

MOS FIELD EFFECT TRANSISTOR

2SK3354

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The 2SK3354 is N-channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

• Super low on-state resistance:

 $R_{DS(on)1}=8.0\,m\Omega$ MAX. (Vgs = 10 V, Ip = 42 A)

 $R_{DS(on)2} = 12 \text{ m}\Omega$ MAX. (Vgs = 4 V, ID = 42 A)

- Low Ciss: Ciss = 6300 pF TYP.
- Built-in gate protection diode

★ ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3354	TO-220AB
2SK3354-S	TO-262
2SK3354-ZJ	TO-263
2SK3354-Z	TO-220SMD ^{Note}

Note TO-220SMD package is produced only in Japan.

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	60	V
Gate to Source Voltage (Vps = 0 V)	VGSS(AC)	±20	V
Drain Current (DC) (Tc = 25°C)	$I_{D(DC)}$	±83	Α
Drain Current (pulse) Note1	I _{D(pulse)}	±332	Α
Total Power Dissipation (Tc = 25°C)	P _{T1}	100	W
Total Power Dissipation (T _A = 25°C)	P_{T2}	1.5	W
Channel Temperature	Tch	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C
Single Avalanche Current Note2	las	55	Α
Single Avalanche Energy Note2	Eas	302	mJ

Notes 1. PW \leq 10 μ s, Duty cycle \leq 1%

2. Starting T_{ch} = 25°C, R_G = 25 Ω , V_{GS} = 20 V \rightarrow 0 V

(TO-220AB)



(TO-262)



(TO-263, TO-220SMD)



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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

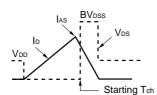


ELECTRICAL CHARACTERISTICS (TA = 25°C)

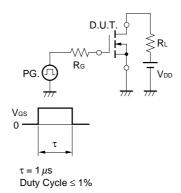
				1	1	
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	Vps = 60 V, Vgs = 0 V			10	μΑ
Gate Leakage Current	lgss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 42 A	35	59		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 42 A		6.3	8.0	mΩ
	RDS(on)2	Vgs = 4 V, ID = 42 A		8.0	12	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		6300		pF
Output Capacitance	Coss			1000		pF
Reverse Transfer Capacitance	Crss			490		pF
Turn-on Delay Time	td(on)	$I_D = 42 \text{ A}, V_{GS(on)} = 10 \text{ V}, V_{DD} = 30 \text{ V},$		100		ns
Rise Time	tr	$R_G = 10 \Omega$		1500		ns
Turn-off Delay Time	t _{d(off)}			300		ns
Fall Time	tr			440		ns
Total Gate Charge	Q _G	ID = 83 A , VDD = 48 V, VGS = 10 V		106		nC
Gate to Source Charge	Qgs			20		nC
Gate to Drain Charge	Q _{GD}			30		nC
Body Diode Forward Voltage	V _F (S-D)	IF = 83 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 83 A, VGS = 0 V,		55		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		100		nC

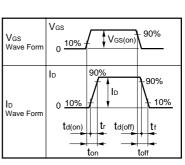
TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c} \text{D.U.T.} \\ \text{Rg} = 25 \ \Omega \\ \text{PG.} \\ \text{Vgs} = 20 \ \text{V} \rightarrow 0 \ \text{V} \\ \end{array}$



TEST CIRCUIT 2 SWITCHING TIME

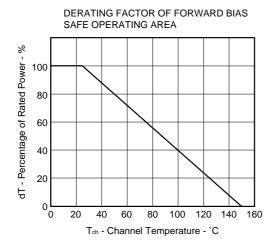


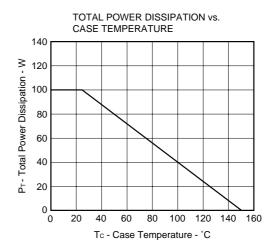


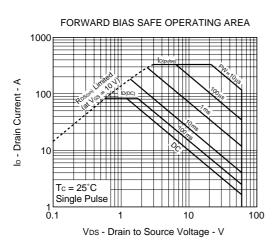
TEST CIRCUIT 3 GATE CHARGE



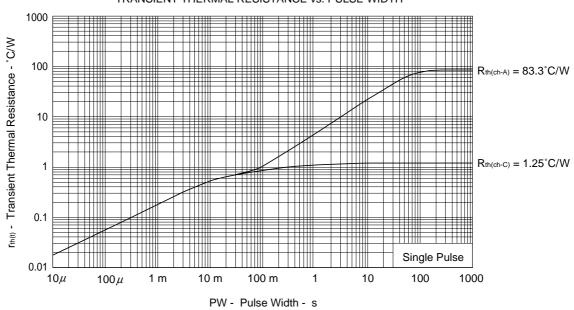
★ TYPICAL CHARACTERISTICS(TA = 25°C)







TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

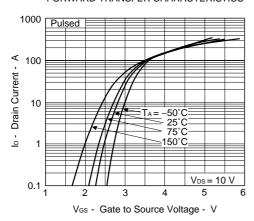


Data Sheet D14131EJ2V0DS

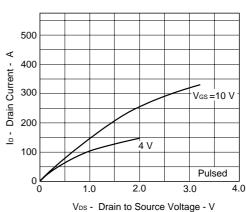
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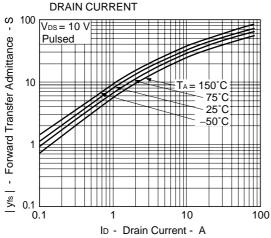
FORWARD TRANSFER CHARACTERISTICS



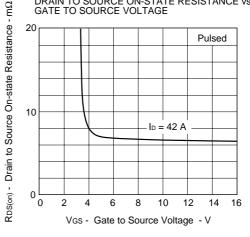
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



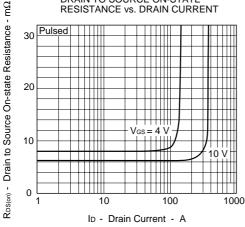
FORWARD TRANSFER ADMITTANCE vs.



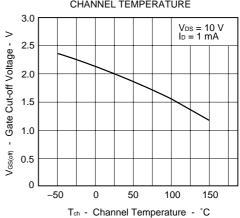
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



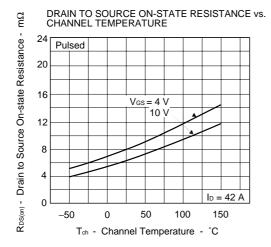
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

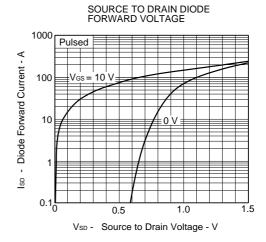


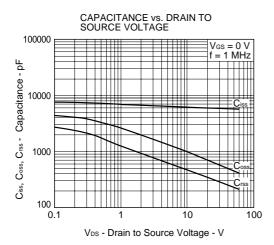
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE

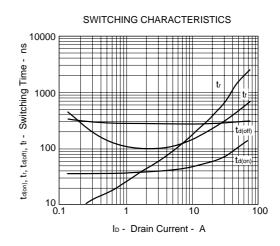


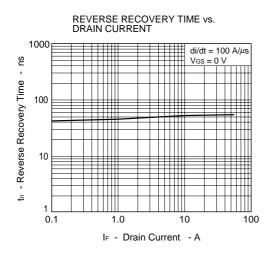


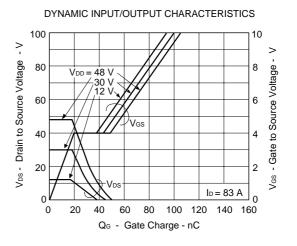




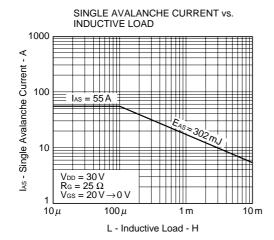


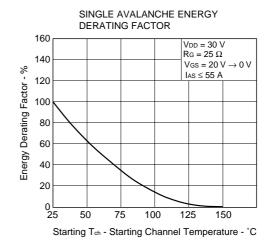






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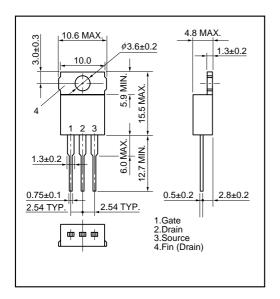




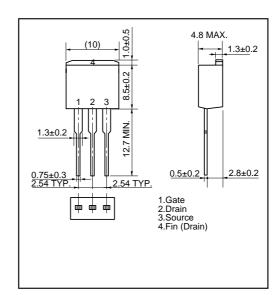


★ PACKAGE DRAWINGS (Unit: mm)

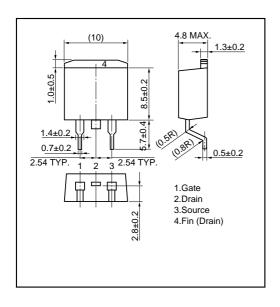
1) TO-220AB(MP-25)



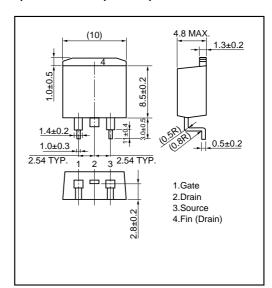
2) TO-262(MP-25 Fin Cut)



3) TO-263 (MP-25ZJ)

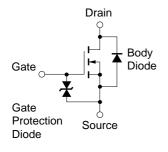


4) TO-220SMD(MP-25Z)^{Note}



Note This Package is produced only in Japan.

EQUIVALENT CIRCUIT



Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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